

Serial EEPROM Series Standard EEPROM SPI BUS EEPROM





BR25Lxxx-W Series 1K 2K 4K 8K 16K 32K 64K)

General Description

BR25Lxxx-W series is a serial EEPROM of SPI BUS interface method.

Features

- High speed clock action up to 5MHz (Max.)
- Wait function by HOLD terminal
- Part or whole of memory arrays settable as read only memory area by program
- 1.8V to 5.5V single power source action most suitable for battery use
- Page write mode useful for initial value write at factory shipment
- Highly reliable connection by Au pad and Au wire
- For SPI bus interface

(CPOL, CPHA) = (0, 0), (1, 1)

- Auto erase and auto end function at data rewrite
- Low current consumption
 - > At write action (5V): 1.5mA (Typ.)
 - At read action (5V): 1.0mA (Typ.)
 - > At standby action (5V) : 0.1µA (Typ.)
- Address auto increment function at read action
- Write mistake prevention function
 - > Write prohibition at power on
 - Write prohibition by command code (WRDI)
 - Write prohibition by WP pin
 - Write prohibition block setting by status registers (BP1, BP0)
 - Write mistake prevention function at low voltage
- Data at shipment Memory array: FFh, status register WPEN, BP1, BP0:0
- Data kept for 40 years
- Data rewrite up to 1,000,000 times

● Packages W(Typ.) x D(Typ.) x H(Max.)



DIP-T8 9.30mm x 6.50mm x 7.10mm



SOP8

5.00mm x 6.20mm x 1.71mm





4.90mm x 6.00mm x 1.65mm



SSOP-B8 3.00mm x 6.40mm x 1.35mm



TSSOP-B8J

3.00mm x 4.90mm x 1.10mm



■Page write

| ,gc | | |
|-------------------|--|--|
| Number of pages | 16Byte | 32Byte |
| Product number | BR25L010-W BR25L020-W BR25L040-W | BR25L080-W BR25L160-W BR25L320-W BR25L640-W |

BR25L Series

| Capacity | Bit format | Type | Power source | DIP-T8 | SOP8 | SOP-J8 | SSOP-B8 | TSSOP-B8 | MSOP8 | TSSOP-B8J |
|----------|-------------|------------|--------------|--------|------|--------|---------|----------|-------|-----------|
| Capacity | DIL IOITIAL | Туре | voltage | | F | FJ | FV | FVT | FVM | FVJ |
| 1Kbit | 128 X 8 | BR25L010-W | 1.8 ~ 5.5V | | • | • | • | • | • | • |
| 2Kbit | 256 X 8 | BR25L020-W | 1.8 ~ 5.5V | | • | • | • | • | • | • |
| 4Kbit | 512 X 8 | BR25L040-W | 1.8 ~ 5.5V | • | • | • | • | • | • | • |
| 8Kbit | 1K X 8 | BR25L080-W | 1.8 ~ 5.5V | • | • | • | • | • | | |
| 16Kbit | 2K X 8 | BR25L160-W | 1.8 ~ 5.5V | • | • | • | • | • | | |
| 32Kbit | 4K X 8 | BR25L320-W | 1.8 ~ 5.5V | • | • | • | | | | |
| 64Kbit | 8K X 8 | BR25L640-W | 1.8 ~ 5.5V | • | • | • | | | | |

OProduct structure: Silicon monolithic integrated circuit OThis product is not designed protection against radioactive rays

● Absolute Maximum Ratings (Ta=25°C)

| Parameter | Symbol | Limits | Unit | Remarks |
|-----------------------------|--------|-----------------|------|---|
| Impressed voltage | Vcc | -0.3 to +6.5 | V | |
| | | 800 (DIP-T8) | | When using at Ta=25°C or higher, 8.0mW to be reduced per 1°C. |
| | | 450 (SOP8) | | When using at Ta=25°C or higher, 4.5mW to be reduced per 1°C. |
| Permissible | | 450 (SOP-J8) | | When using at Ta=25°C or higher, 4.5mW to be reduced per 1°C. |
| dissipation | Pd 300 | 300 (SSOP-B8) | mW | When using at Ta=25°C or higher, 3.0mW to be reduced per 1°C. |
| | | 330 (TSSOP-B8) | | When using at Ta=25°C or higher, 3.3mW to be reduced per 1°C. |
| | | 310 (MSOP8) | | When using at Ta=25°C or higher, 3.1mW to be reduced per 1°C. |
| | | 310 (TSSOP-B8J) | | When using at Ta=25°C or higher, 3.1mW to be reduced per 1°C. |
| Storage temperature range | Tstg | -65 to +125 | °C | |
| Operating temperature range | Topr | -40 to +85 | °C | |
| Terminal Voltage | - | -0.3 to Vcc+0.3 | V | |

● Memory cell characteristics (Ta=25°C, Vcc=1.8V to 5.5V)

| Parameter | | Unit | | |
|---------------------------------|-----------|------|------|-------|
| Farameter | Min. | Тур. | Max. | Unit |
| Number of data rewrite times *1 | 1,000,000 | - | - | Times |
| Data hold years *1 | 40 | - | - | Years |

^{*1} Not 100% TESTED

Recommended Operating Ratings

| Parameter | Symbol | Limits | Unit |
|----------------------|--------|------------|------|
| Power source voltage | Vcc | 1.8 to 5.5 | \/ |
| Input voltage | Vin | 0 to Vcc | V |

●Input / output capacity (Ta=25°C, frequency=5MHz)

| Parameter | Symbol | Min. | Max. | Unit | Conditions |
|--------------------|------------------|------|------|------|-----------------------|
| Input capacity *1 | C _{IN} | _ | 8 | n E | V _{IN} =GND |
| Output capacity *1 | C _{OUT} | _ | 8 | p⊦ | V _{OUT} =GND |

^{*1} Not 100% TESTED.

● Electrical Characteristics (Unless otherwise specified, Ta=-40°C to +85°C, Vcc=1.8V to 5.5V)

| Parameter | Symbol | Limits | | | Unit | Conditions |
|-------------------------------------|--------|---------|------|---------|-------|--|
| Farameter | Symbol | Min. | Тур. | Max. | Ullit | Conditions |
| "H" input voltage1 | VIH | 0.7Vcc | _ | Vcc+0.3 | V | 1.8V≦Vcc≦5.5V |
| "L" input voltage1 | VIL | -0.3 | _ | 0.3Vcc | V | 1.8V≦Vcc≦5.5V |
| "L" output voltage1 | VOL1 | 0 | _ | 0.4 | V | IOL=2.1mA(Vcc=2.5V to 5.5V) |
| "L" output voltage2 | VOL2 | 0 | _ | 0.2 | V | IOL=150µA(Vcc=1.8V to 2.5V) |
| "H" output voltage1 | VOH1 | Vcc-0.5 | _ | Vcc | V | IOH=-0.4mA(Vcc=2.5V to 5.5V) |
| "H" output voltage2 | VOH2 | Vcc-0.2 | _ | Vcc | V | IOH=-100μA(Vcc=1.8V to 2.5V) |
| Input leak current | ILI | -1 | _ | 1 | μΑ | V _{IN} =0 to Vcc |
| Output leak current | ILO | -1 | _ | 1 | μΑ | VOUT=0 to Vcc, CS=Vcc |
| Command assessment as at | Icc1 | _ | _ | 1.0 | mA | Vcc=1.8V, fSCK=2MHz, tE/W=5ms Byte write, Page write, Write status register |
| Current consumption at write action | Icc2 | _ | _ | 2.0 | mA | Vcc=2.5V, fSCK=5MHz, tE/W=5ms Byte write, Page write, Write status register |
| | Icc3 | _ | _ | 3.0 | mA | Vcc=5.5V, fSCK=5MHz, tE/W=5ms Byte write, Page write, Write status register |
| Current consumption at | Icc4 | _ | _ | 1.5 | mA | Vcc=2.5V, fSCK=5MHz Read, Read status register |
| read action | Icc5 | _ | _ | 2.0 | mA | Vcc=5.5V, fSCK=5MHz Read, Read status register |
| Standby current | ISB | _ | _ | 2 | μΑ | Vcc=5.5V,SO=OPEN CS=HOLD=WP=Vcc, SCK=SI=Vcc or =GND |

●Operating timing characteristics (Ta=-40°C to +85°C, unless otherwise specified, load capacity C_{L1} 100pF)

| Description | | | ≦Vcc< | | | ≤Vcc∙ | | Unit |
|-------------------------------------|--------|------|-------|------|------|-------|------|------|
| Parameter | Symbol | Min. | Тур. | Max. | Min. | Тур. | Max. | Unit |
| SCK frequency | fSCK | - | - | 2 | - | - | 5 | MHz |
| SCK high time | tSCKWH | 200 | - | - | 85 | - | - | ns |
| SCK low time | tSCKWL | 200 | - | - | 85 | - | - | ns |
| CS high time | tCS | 200 | - | - | 85 | - | - | ns |
| CS setup time | tCSS | 200 | - | - | 90 | - | - | ns |
| CS hold time | tCSH | 200 | - | - | 85 | - | - | ns |
| SCK setup time | tSCKS | 200 | - | - | 90 | - | - | ns |
| SCK hold time | tSCKH | 200 | - | - | 90 | - | - | ns |
| SI setup time | tDIS | 40 | - | - | 20 | - | - | ns |
| SI hold time | tDIH | 50 | - | - | 40 | - | - | ns |
| Data output delay time 1 | tPD1 | - | - | 150 | - | - | 70 | ns |
| Data output delay time 2 (CL2=30pF) | tPD2 | - | - | 145 | - | - | 55 | ns |
| Output hold time | tOH | 0 | - | - | 0 | - | - | ns |
| Output disable time | tOZ | - | - | 250 | - | - | 100 | ns |
| HOLD setting setup time | tHFS | 120 | - | - | 60 | - | - | ns |
| HOLD setting hold time | tHFH | 90 | - | - | 40 | - | - | ns |
| HOLD release setup time | tHRS | 120 | - | - | 60 | - | - | ns |
| HOLD release hold time | tHRH | 140 | - | - | 70 | - | - | ns |
| Time from HOLD to output High-Z | tHOZ | - | - | 250 | - | - | 100 | ns |
| Time from HOLD to output change | tHPD | - | - | 150 | - | - | 70 | ns |
| SCK rise time | tRC | - | - | 1 | - | - | 1 | μs |
| SCK fall time | tFC | - | - | 1 | - | - | 1 | μs |
| OUTPUT rise time | tRO | - | - | 100 | - | - | 50 | ns |
| OUTPUT fall time | tFO | - | - | 100 | - | - | 50 | ns |
| Write time | tE/W | - | - | 5 | - | - | 5 | ms |

^{*1} NOT 100% TESTED

●AC measurement conditions

| Parameter | Symbol | | Unit | | |
|---------------------------------|-----------------|---------------|------|------|-------|
| Falametei | Symbol | Min. | Тур. | Max. | Offic |
| Load capacity 1 | C _{L1} | - | - | 100 | pF |
| Load capacity 2 | C _{L2} | | | 30 | pF |
| Input rise time | - | - | - | 50 | ns |
| Input fall time | - | - | - | 50 | ns |
| Input voltage | - | 0.2Vcc/0.8Vcc | | | V |
| Input / output judgment voltage | - | 0.3Vcc/0.7Vcc | | | V |

●Sync data input / output timing

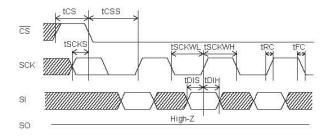


Figure 1. Input timing

SI is taken into IC inside in sync with data rise edge of SCK. Input address and data from the most significant bit MSB.

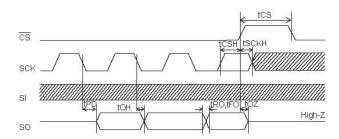


Figure 2. Input / output timing

SO is output in sync with data fall edge of SCK. Data is output from the most significant bit MSB.

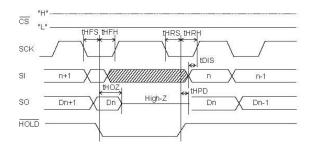
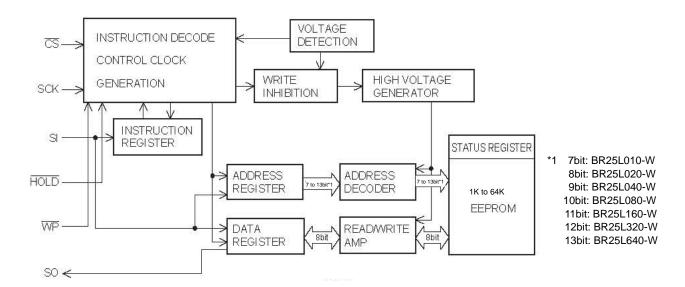
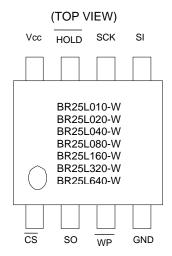


Figure 3. HOLD timing

●Block Diagram



●Pin Configuration



Pin Descriptions

| Terminal name | Input /output | Function |
|---------------|------------------|--|
| Vcc | - | Power source to be connected |
| GND | - | All input / output reference voltage, 0V |
| CS | Input | Chip select input |
| SCK | Input | Serial clock input |
| SI | Input | Start bit, ope code, address, and serial data input |
| SO | Output | Serial data output |
| HOLD | Input | Hold input Command communications may be suspended temporarily (HOLD status). |
| WP | Input | Write protect input Write command is prohibited. *1 Write status register command is prohibited. |

*1:BR25L010/020/040-W

●Typical Performance Curves

(The following characteristic data are Typ. Values.)

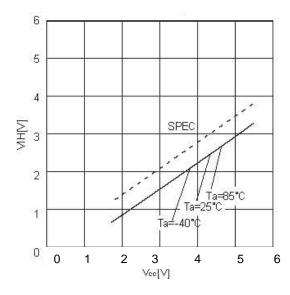


Figure 4. "H" input voltage VIH
(CS,SCK,SI,HOLD,WP)

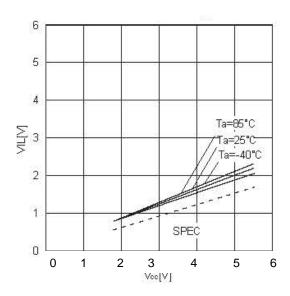


Figure 5. "L" input voltage VIL

(CS,SCK,SI,HOLD,WP)

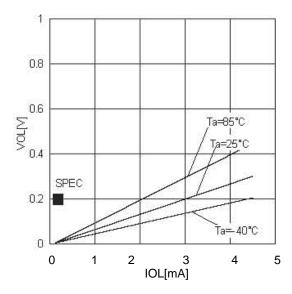


Figure 6. "L" output voltage VOL-IOL(Vcc=1.8V)

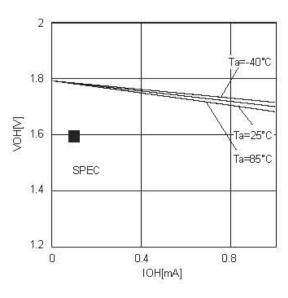
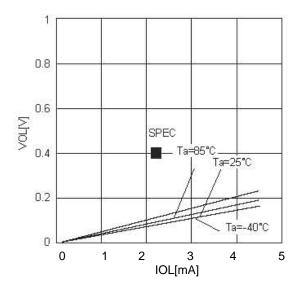
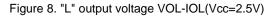


Figure 7. "H" output voltage VOH-IOH (Vcc=1.8V)





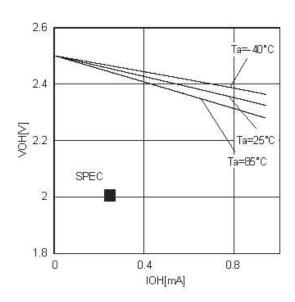


Figure 9. "H" output voltage VOH-IOH(Vcc=2.5V)

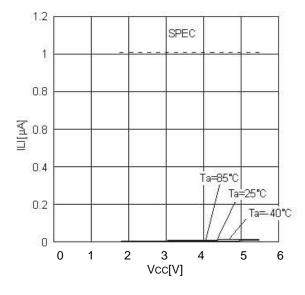


Figure 10. Input leak current ILI
(CS,SCK,SI,WP,HOLD)

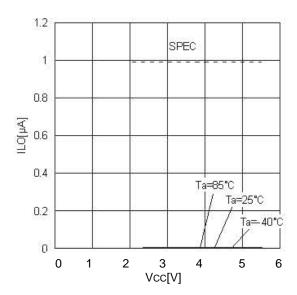
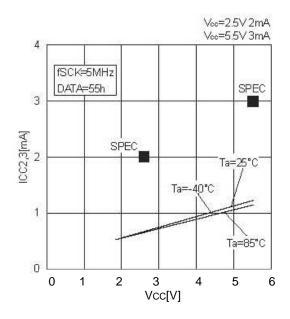


Figure 11. Output leak current ILO(SO)



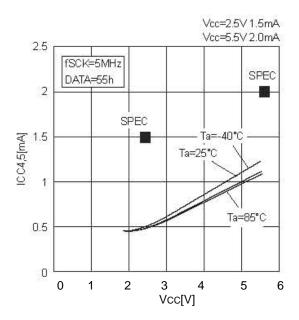
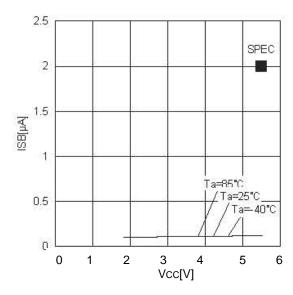


Figure 12. Current consumption at WRITE operation ICC1,2,3 (WRITE,PAGE WRITE,WRSR,fSCK=5MHz) BR25L010-W,BR25L020-W,BR25L040-W

Figure 13. Consumption current at READ operation ICC4,5 (READ, WRSR,fSK=5MHz)





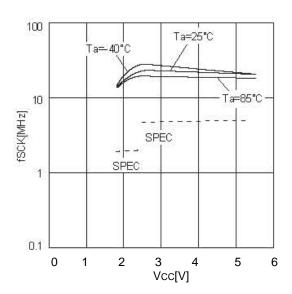
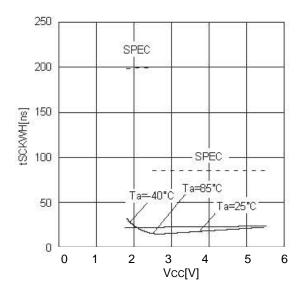
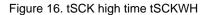


Figure 15. SCK frequency tSCK





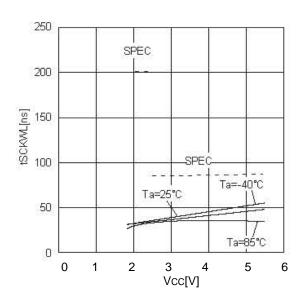


Figure 17. SCK low time tSCKWL

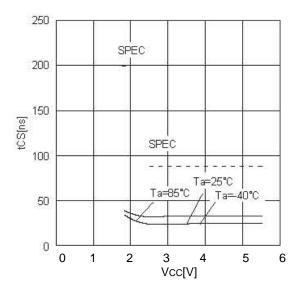


Figure 18. CS high time tCS

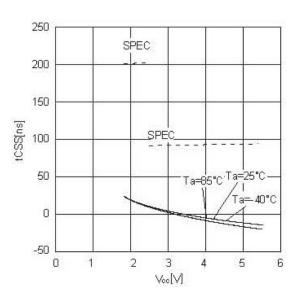


Figure 19. CS setup time tCSS

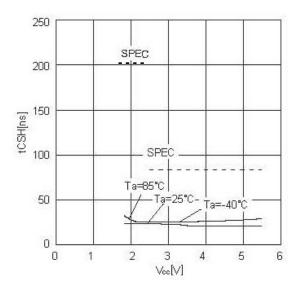


Figure 20. CS hold time tCSH

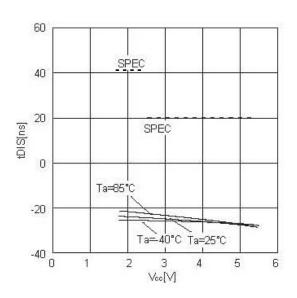


Figure 21. SI setup time tDIS

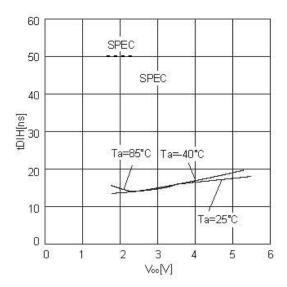


Figure 22. SI hold time tDIH

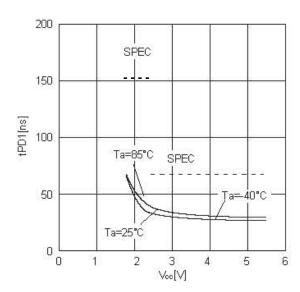
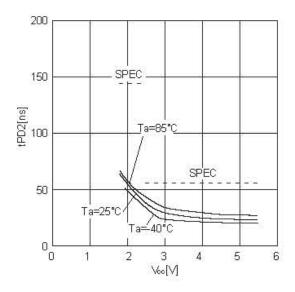


Figure 23. Data output delay time tPD1(CL=100pF)



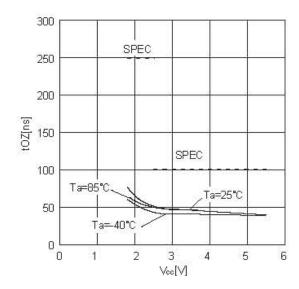


Figure 24. Data output delay time tPD2(CL=30pF)

Figure 25. Output disable time tOZ

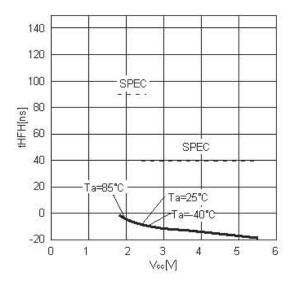


Figure 26. HOLD setting hold time tHFH

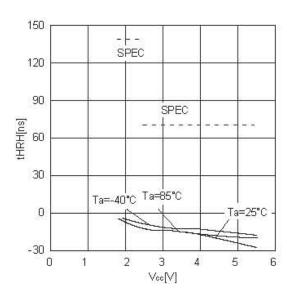
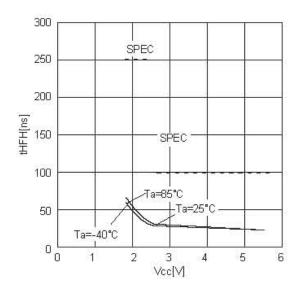


Figure 27. HOLD release hold time tHRH



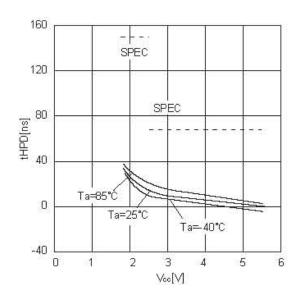


Figure 28. Time from HOLD to output High-Z tHOZ

Figure 29. Time from HOLD to output change tHPO

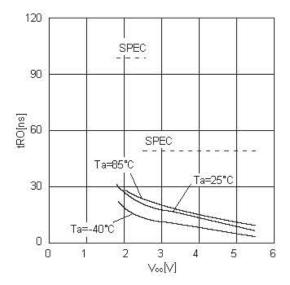


Figure 30. Output rise time tRO

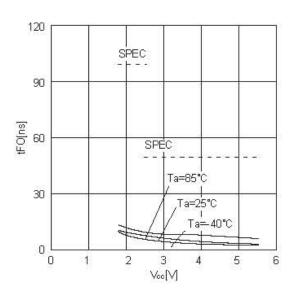


Figure 31. Output fall time

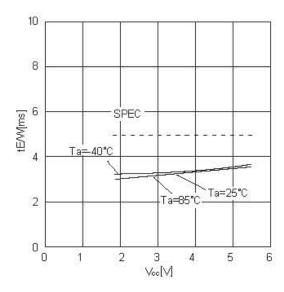


Figure 32. Write cycle time tE/W

Features

OStatus registers

This IC has status registers. The status registers are of 8 bits and express the following parameters.

BP0 and BP1 can be set by write status register command. These 2 bits are memorized into the EEPROM, therefore are valid even when power source is turned off.

Rewrite characteristics and data hold time are same as characteristics of the EEPROM.

WEN can be set by <u>write</u> enable command and write disable command. WEN becomes write disable status when power source is turned off. R/B is for write confirmation, therefore cannot be set externally.

The value of status register can be read by read status command.

Status registers

| Product number | bit 7 | bit 6 | bit 5 | bit 4 | bit 3 | bit 2 | bit 1 | bit 0 |
|----------------|-------|-------|-------|-------|-------|-------|-------|----------|
| BR25L010-W | | | | | | | | |
| BR25L020-W | 1 | 1 | 1 | 1 | BP1 | BP0 | WEN | _ R/B |
| BR25L040-W | | | | | | | | |
| BR25L080-W | | | | | | | | |
| BR25L160-W | | | | | | | | = |
| BR25L320-W | WPEN | 0 | 0 | 0 | BP1 | BP0 | WEN | R/B |
| BR25L640-W | | | | | | | | |

| bit | Memory location | Function | Contents |
|------------|-----------------|---|---|
| WPEN | EEPROM | WP pin enable / disable designation bit WPEN=0=invalid WPEN=1=valid | Th <u>is e</u> nables / disables the functions of WP pin. |
| BP1 BP0 | EEPROM | EEPROM write disable block designation bit | This designates the write disable area of EEPROM. Write designation areas of product numbers are shown below. |
| WEN | Register | Write and write status register write enable / disable status confirmation bit WEN=0=prohibited WEN=1=permitted | |
| _ R/B | Register | Write cycle status (READY / BUSY) status confirmation bit | |

Write disable block setting

| BP1 | BP0 | Write disable block | | | | | | |
|-----|-----|---------------------|------------|------------|------------|------------|------------|-------------|
| | | BR25L010-W | BR25L020-W | BR25L040-W | BR25L080-W | BR25L160-W | BR25L320-W | BR25L640-W |
| 0 | 0 | None | None | None | None | None | None | None |
| 0 | 1 | 60h-7Fh | C0h-FFh | 180h-1FFh | 300h-3FFh | 600h-7FFh | C00h-FFFh | 1800h-1FFFh |
| 1 | 0 | 40h-7Fh | 80h-FFh | 100h-1FFh | 200h-3FFh | 400h-7FFh | 800h-FFFh | 1000h-1FFFh |
| 1 | 1 | 00h-7Fh | 00h-FFh | 000h-1FFh | 000h-3FFh | 000h-7FFh | 000h-FFFh | 0000h-1FFFh |

OWP pin

By <u>setting WP=LOW</u>, write command is prohibited. As for BR25L080, 160, 320, 640-W, only when WPEN bit is set "1", the WP pin functions become valid. And the write command to be disabled at this moment is WRSR. As for BR25L010, 020, 040-W, both WRITE and WRSR commands are prohibited.

However, when write cycle is in execution, no interruption can be made.

| Product number | WRSR | WRITE |
|----------------|----------------------|-------------|
| BR25L010-W | Prohibition | Prohibition |
| BR25L020-W | possible | possible |
| BR25L040-W | | |
| BR25L080-W | | |
| BR25L160-W | Prohibition possible | Prohibition |
| BR25L320-W | but WPEN bit "1" | impossible |
| BR25L640-W | | |

OHOLD pin

By $\overline{\text{HOLD}}$ pin, data transfer can be interrupted. When SCK="1", by making $\overline{\text{HOLD}}$ from "1" into"0", data transfer to EEPROM is interrupted. When SCK = "0", by making HOLD from "0" into "1", data transfer is restarted.

■Command mode

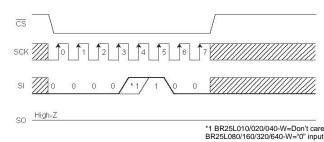
| | | | Ope code | | | | | |
|-------|-----------------------|-------------------------------|------------------|-------|--------|-------|--------------------------------------|---------------|
| | Command | Contents | BR25L0 BR25L0 | - | BR25L0 |)40-W | BR25L0 BR25L1 BR25L3 BR25L6 | 60-W 320-W |
| WREN | Write enable | Write enable command | 0000 | * 110 | 0000 | * 110 | 0000 | 0110 |
| WRDI | Write disable | Write disable command | 0000 | * 100 | 0000 | * 100 | 0000 | 0100 |
| READ | Read | Read command | 0000 | * 011 | 0000 | A8011 | 0000 | 0011 |
| WRITE | Write | Write command | 0000 | * 010 | 0000 | A8010 | 0000 | 0010 |
| RDSR | Read status register | Status register read command | 0000 | * 101 | 0000 | * 101 | 0000 | 0101 |
| WRSR | Write status register | Status register write command | 0000 | * 001 | 0000 | * 001 | 0000 | 0001 |

Timing chart

SO High-Z

1. Write enable (WREN) / disable (WRDI) cycle

WREN (WRITE ENABLE): Write enable



WRDI (WRITE DISABLE): Write disable

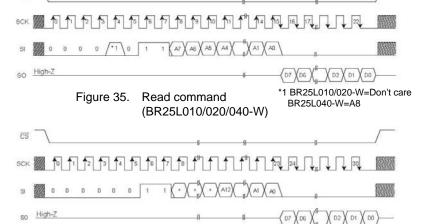
Figure 33. Write enable command

*1 BR25L010/020/040-W=Don't care

Figure 34. Write disable

○This IC has write enable status and write disable status. It is set to write enable status by write enable command, and it is set to write disable status by write disable command. As for these commands, set CS LOW, and then input the respective ope codes. The respective commands accept command at the 7-th clock rise. Even with input over 7 clocks, command becomes valid. When to carry out write and write status register command, it is necessary to set write enable status by the write enable command. If write or write status register command is input in the write disable status, commands are cancelled. And even in the write enable status, once write and write status register command is executed once, it gets in the write disable status. After power on, this IC is in write disable status.

2. Read command (READ)



| Figure 36. | Read command | * =Don't care |
|------------|--------------------------|---------------|
| | (BR25L080/160/320/640-W) | |

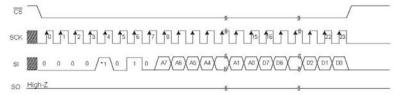
| Product | Address |
|------------|---------|
| number | length |
| BR25L010-W | A6-A0 |
| BR25L020-W | A7-A0 |
| BR25L040-W | A8-A0 |

| Product | Address |
|------------|---------|
| number | length |
| BR25L080-W | A9-A0 |
| BR25L160-W | A10-A0 |
| BR25L320-W | A11-A0 |
| BR25L640-W | A12-A0 |

By read command, data of EEPROM can be read. As for this command, set \overline{CS} LOW, then input address after read ope code. EEPROM starts data output of the designated address. Data output is started from SCK fall of 15/23¹ clock, and from D7 to D0 sequentially. This IC has increment read function. After output of data for 1 byte (8 bits), by continuing input of SCK, data of the next address can be read. Increment read can read all the addresses of EEPROM. After reading data of the most significant address, by continuing increment read, data of the most insignificant address is read.

*1 BR25L010/020/040-W=15 clocks BR25L080/160/320/640-W=23 clocks

3. Write command (WRITE)



| Product | Address |
|------------|---------|
| number | length |
| BR25L010-W | A6-A0 |
| BR25L020-W | A7-A0 |
| BR25L040-W | A8-A0 |

Figure 37. Write command (BR25L010/020/040-W)

| 1 | BR25L010/020-W=Don't care |
|---|---------------------------|
| | BR25L040-W=A8 |

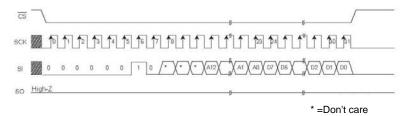


Figure 38. Write command (BR25L080/160/320/640-W)

| Product | Address |
|------------|---------|
| number | length |
| BR25L080-W | A9-A0 |
| BR25L160-W | A10-A0 |
| BR25L320-W | A11-A0 |
| BR25L640-W | A12-A0 |

By write command, data of EEPROM can be written. As for this command, set \overline{CS} LOW, then input address and data after write ope code. Then, by making \overline{CS} HIGH, the EEPROM starts writing. The write time of EEPROM requires time of tE/W (Max 5ms). During tE/W, other than status read command is not accepted. Start \overline{CS} after taking the last data (D0), and before the next SCL clock starts. At other timing, write command is not executed, and this write command is cancelled. This IC has page write function, and after input of data for 1 byte (8 bits), by continuing data input without starting \overline{CS} , data up to $16/32^{\circ}1$ bytes can be written for one tE/W. In page write, the insignificant $4/5^{\circ}2$ bit of the designated address is incremented internally at every time when data of 1 byte is input, and data is written to respective addresses. When data of the maximum bytes or higher is input, address rolls over, and previously input data is overwritten.

^{*1} BR25L010/020/040-W=16 bytes at maximum BR25L080/160/320/640-W=32 bytes at maximum

^{*2} BR25L010/020/040-W=Insignificant 4 bits BR25L080/160/320/640-W=Insignificant 5 bits

4. Status register write / read command

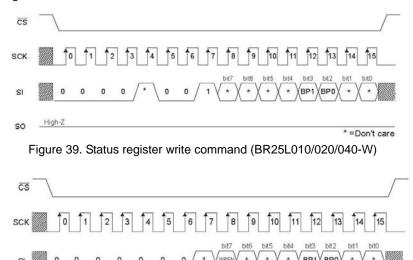


Figure 40. Status register write command (BR25L080/160/320/640-W)

Write status register command can write status register data. The data the can be written by this command are 2 bits *1, that is, BP1 (bit3) and BP0 (bit2) among 8 bits of status register. By BP1 and BP0, write disable block of EEPROM can be set. As for this command, set CS LOW, and input ope code of write status register, and input data. Then, by making CS HIGH, EEPROM starts writing. Write time requires time of tE/W as same as write. As for CS rise, start CS after taking the last data bit (bit0), and before the next SCK clock starts. At other timing, command is cancelled. Write disable block is determined by BP1 and BP0, and the block can be selected from 1/4 of memory array, 1/2, and entire memory array. (Refer to the write disable block setting table.) To the write disabled block, write cannot be made, and only read can be made.

* 3 bits including BR25L080, 160, 320, 640-W WPEN (bit7)

=Don't care

Figure 41. Status register read command (BR25L010/020/040-W)

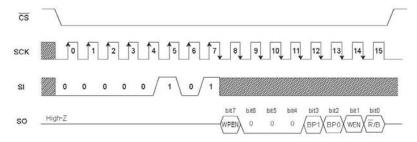


Figure 42. Status register read command (BR25L080/160/320/640-W)

At standby

Current at standby

Set CS "H", and be sure to set SCK, SI, WP, HOLD input "L" or "H". Do not input intermediate electric potential.

As shown in Figure 43, at standby, when SCK is "H", even if CS is fallen, SI status is not read at fall edge. SI status is read at SCK rise edge after fall of CS. At standby and at power ON/OFF, set CS "H" status.

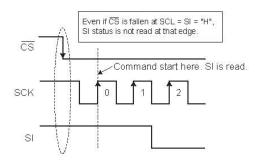


Figure 43. Operating timing

WP cancel valid area

WP is normally fixed to "H" or "L" for use, <u>but</u> when WP is controlled so as to cancel write status register command and write command, pay attention to the following WP valid timing.

While write or write status register command is executed, by setting WP = "L" in cancel valid area, command can be cancelled. The area from command ope code before CS rise at internal automatic write start becomes the cancel valid area. However, once write is started, any input cannot be cancelled. WP input becomes Don't Care, and cancellation becomes invalid.

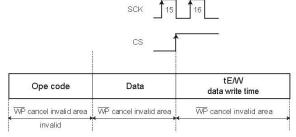


Figure 44. WP valid timing (WRSR)

| Ope code | Address | Data | tE/VV data write time |
|------------------------|------------------------|------|--------------------------|
| WP cancel invalid area | WP cancel invalid area | | WP cancel invalid area |
| invalid | valid | | 1 |

Figure 45. WP valid timing (WRITE)

●HOLD pin

By HOLD pin, command communication can be stopped temporarily. (HOLD status) The HOLD pin carries out command communications normally when it is HIGH. To get in HOLD status, at command communication, when SCK = LOW, set the HOLD pin LOW. At HOLD status, SCK and SI become Don't Care, and SO becomes high impedance (High-Z). To release the HOLD status, set the HOLD pin HIGH when SCK = LOW. After that, communication can be restarted from the point before the HOLD status. For example, when HOLD status is made after A5 address input at read, after release of HOLD status, by starting A4 address input, read can be restarted. When in HOLD status, leave CS LOW. When it is set CS = HIGH in HOLD status, the IC is reset, therefore communication after that cannot be restarted.

Method to cancel each command

OREAD, RDSR

• Method to cancel: cancel by CS = "H".

| Ope code | Address | Data | | | |
|--|---------|--------|--|--|--|
| 8 bits | ε bits | 8 bits | | | |
| Cancel available in all areas of read mode | | | | | |

Figure 46. READ cancel valid timing

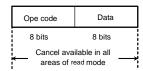


Figure 47. RDSR cancel valid timing

OWRITE, PAGE WRITE

- a : Ope code, address input area. Cancellation is available by CS="H".
- b : Data input area (D7 to D1 input area) Cancellation is available by CS="H".
- c : Data input area (D0 area)

 When CS is started, write starts.

 After CS rise, cancellation cannot be made by any means.
- d: tE/W area

 Cancellation is available by CS = "H". However, when write starts (CS is started) in the area c, cancellation cannot be made by any means. And, by inputting on SCK clock, cancellation cannot be made. In page write mode, there is write enable area at every 8 clocks.

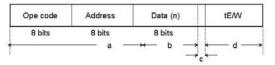
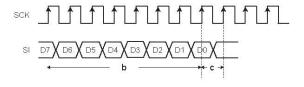


Figure 48. WRITE cancel valid timing



Note1) If <u>Vcc</u> is made OFF during write execution, designated address data is not guaranteed, therefore write it once again. Note2) If CS is started at the same timing as that of the SCK rise, write execution / cancel becomes unstable, therefore, it is recommended to fall in SCK = "L" area. As for SCK rise, assure timing of tCSS / tCSH or higher.

OWRSR

- a : From ope <u>code</u> to 15 clock rise Cancel by CS="H".
- b : From 15 clock rise to 16 clock rise (write enable area) When CS is started, write starts.

 After CS rise, cancellation cannot be made by any means.
- c : After 16 clock rise.

Cancel by $\overline{\text{CS}}$ ="H". However, when write starts $\overline{\text{CS}}$ is started) in the area b, cancellation cannot be made by any means. And, by inputting on SCK clock, cancellation cannot be made.

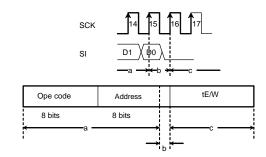


Figure 49. WRSR cancel valid timing

Note1) If Vcc is made OFF during write execution, designated address data is not guaranteed, therefore write it once again.

Note2) If CS is started at the same timing as that of the SCK rise, write execution / cancel becomes unstable, therefore, it is recommended to fall in SCK = "L" area. As for SCK rise, assure timing of tCSS/tCSH or higher.

OWREN/WRDI

- a : From ope code to clock rise, cancel by \overline{CS} = "H".
- b : Cancellation is not available when $\overline{\text{CS}}$ is started after 7 clock.

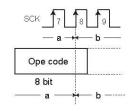


Figure 50. WREN/WRDI cancel valid timing

High speed operation

In order to realize stable high speed operations, pay attention to the following input / output pin conditions.

Olnput pin pull up, pull down resistance

When to attach pull up, pull down resistance to EEPROM input pin, select an appropriate value for the microcontroller VOL, IOL from VIL characteristics of this IC.

OPull up resistance

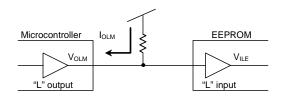


Figure 51. Pull up resistance

$$R_{PU} \ge \frac{V_{CC} - V_{OLM}}{I_{OLM}} \qquad \cdots \textcircled{1}$$

$$V_{OLM} \le V_{ILE} \qquad \cdots \textcircled{2}$$

Example) When Vcc=5V, V_{ILM} =1.5V, V_{OLM} =0.4V, I_{OLM} =2mA, from the equation ①,

R_{PU}
$$\geq \frac{5-0.4}{2\times10^{-3}}$$

∴R_{PU} $\geq 2.3[kΩ]$

With the value of Rpu to satisfy the above equation, V_{OLM} becomes 0.4V or higher, and with V_{ILE} (=1.5V), the equation ② is also satisfied.

- V_{ILM} :EEPROM V_{IH} specifications
- V_{OLM}: Microcontroller V_{OL} specifications
- · I_{OLM} :Microcontroller I_{OL} specifications

And, in order to prevent malfunction, mistake write at power ON/OFF, be sure to make CS pull up.

OPull down resistance

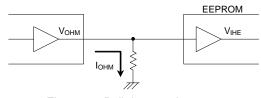


Figure 52. Pull down resistance

$$R_{PD} \ge \frac{V_{OHM}}{I_{OHM}} \cdots 3$$
 $V_{OHM} \ge V_{IHE} \cdots 4$

Example) When V_{CC} =5V, V_{OHM} = V_{CC} -0.5V, I_{OHM} =0.4mA, V_{IHM} = V_{CC} ×0.7V, from the equation③,

$$R_{PD} \ge \frac{5-0.5}{0.4 \times 10^{-3}}$$
$$\therefore R_{PD} \ge 11.3 [k\Omega]$$

Further, by amplitude VIHE, VILE of signal input to EEPROM, operation speed changes. By inputting signal of amplitude of Vcc / GND level to input, more stable high speed operations can be realized. On the contrary, when amplitude of 0.8Vcc / 0.2Vcc is input, operation speed becomes slow.

In order to realize more stable high speed operation, it is recommended to make the values of RPU, RPD as large as possible, and make the amplitude of signal input to EEPROM close to the amplitude of Vcc / GND level. (*1 At this moment, operating timing guaranteed value is guaranteed.)

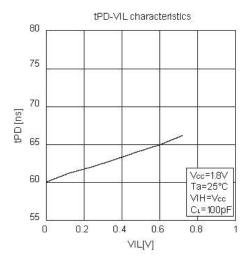


Figure 53. VIL dependency of data output delay time

OSO load capacity condition

Load capacity of SO output pin affects upon delay characteristic of SO output. (Data output delay time, time from HOLD to High-Z) In order to make output delay characteristic into higher speed, make SO load capacity small. In concrete, "Do not connect many devices to SO bus", "Make the wire between the controller and EEPROM short", and so forth.

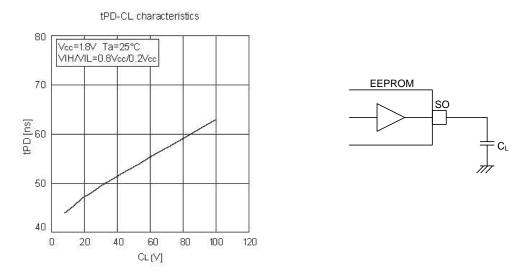


Figure 54. SO load dependency of data output delay time

OOther cautions

Make the wire length from the microcontroller to EEPROM input signal same length, in order to prevent setup / hold violation to EEPROM, owing to difference of wire length of each input.

●Equivalent circuit

OOutput circuit

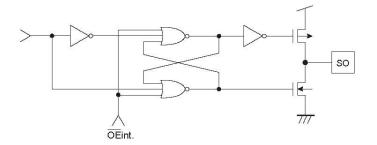


Figure 55. SO output equivalent circuit

Olnput circuit

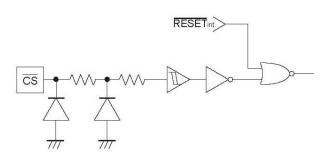


Figure 56. CS input equivalent circuit

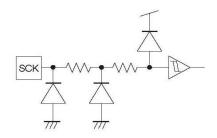


Figure 57. SCK input equivalent circuit

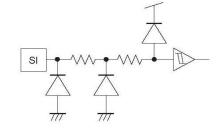


Figure 58. SI input equivalent circuit

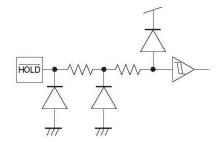


Figure 59. HOLD input equivalent circuit

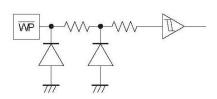


Figure 60. WP input equivalent circuit

●Notes on power ON/OFF

OAt power ON/OFF, set \overline{CS} "H" (= Vcc).

When $\overline{\text{CS}}$ is "L", this IC gets in input accept status (active). If power is turned on in this status, noises and the likes may cause malfunction, mistake write or so. To prevent these, at power ON, set $\overline{\text{CS}}$ "H". (When $\overline{\text{CS}}$ is in "H" status, all inputs are canceled.)

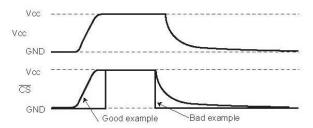


Figure 61. CS timing at power ON/OFF

(Good example) CS terminal is pulled up to Vcc.

At power OFF, take 10ms or higher before re supply. If power is turned on without observing this condition, the IC internal circuit may not be reset, which please note.

(Bad example) CS terminal is "L" at power ON/OFF.

In this case, CS always becomes "L" (active status), and EEPROM may have malfunction, mistake write owing to noises and the likes.

Even when CS input is High-Z, the status becomes like this case, which please note.

OPOR circuit

This IC has a POR (Power On Reset) circuit as mistake write countermeasure. After POR action, it gets in write disable status. The POR circuit is valid only when power is ON, and does not work when power is OFF. When power is ON, if the recommended conditions of the following tR, tOFF, and Vbot are not satisfied, it may become write enable status owing to noises and the likes.

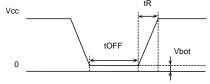


Figure 62. Rise waveform

Recommended conditions of t_R, t_{OFF}, Vbot

| tR | tOFF | Vbot |
|----------------|----------------|---------------|
| 10ms or below | 10ms or higher | 0.3V or below |
| 100ms or below | 10ms or higher | 0.2V or below |

Noise countermeasures

OVcc noise (bypass capacitor)

When noise or surge gets in the power source line, malfunction may occur, therefore, for removing these, it is recommended to attach a by pass capacitor (0.1µF) between IC Vcc and GND. At that moment, attach it as close to IC as possible.

And, it is also recommended to attach a bypass capacitor between board Vcc and GND.

○SCK noise

When the rise time (tR) of SCK is long, and a certain degree or more of noise exists, malfunction may occur owing to clock bit displacement.

To avoid this, a Schmitt trigger circuit is built in SCK input. The hysteresis width of this circuit is set about 0.2V, if noises exist at SCK input, set the noise amplitude 0.2Vp-p or below. And it is recommended to set the rise time (tR) of SCK 100ns or below. In the case when the rise time is 100ns or higher, take sufficient noise countermeasures. Make the clock rise, fall time as small as possible.

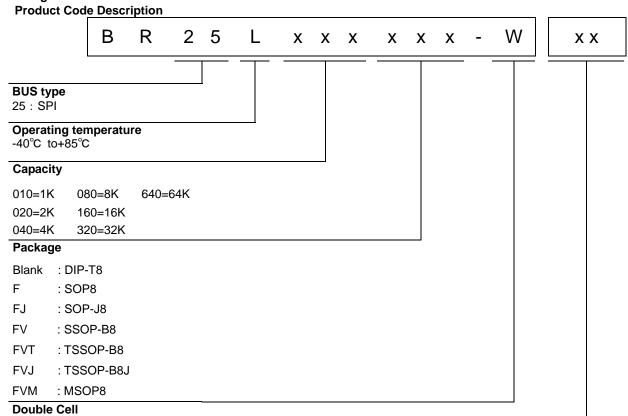
○WP noise

During execution of write status register command, if there exist noises on $\overline{\text{WP}}$ pin, mistake in recognition may occur and forcible cancellation may result, which please note. To avoid this, a Schmitt trigger circuit is built in $\overline{\text{WP}}$ input. In the same manner, a Schmitt trigger circuit is built in SI input and $\overline{\text{HOLD}}$ input too.

Cautions on use

- (1) Described numeric values and data are design representative values, and the values are not guaranteed.
- (2) We believe that application circuit examples are recommendable, however, in actual use, confirm characteristics further sufficiently. In the case of use by changing the fixed number of external parts, make your decision with sufficient margin in consideration of static characteristics and transition characteristics and fluctuations of external parts and our LSI.
- (3) Absolute maximum ratings
 - If the absolute maximum ratings such as impressed voltage and operating temperature range and so forth are exceeded, LSI may be destructed.
 - Do not impress voltage and temperature exceeding the absolute maximum ratings. In the case of fear exceeding the absolute maximum ratings, take physical safety countermeasures such as fuses, and see to it that conditions exceeding the absolute maximum ratings should not be impressed to LSI.
- (4) GND electric potential
 - Set the voltage of GND terminal lowest at any action condition. Make sure that each terminal voltage is lower than that of GND terminal.
- (5) Heat design
 - In consideration of permissible dissipation in actual use condition, carry out heat design with sufficient margin.
- (6) Terminal to terminal short circuit and wrong packaging When to package LSI onto a board, pay sufficient attention to LSI direction and displacement. Wrong packaging may destruct LSI. And in the case of short circuit between LSI terminals and terminals and power source, terminal and GND owing to foreign matter, LSI may be destructed.
- (7) Use in a strong electromagnetic field may cause malfunction, therefore, evaluate design sufficiently.

Ordering Information



Package specifications

E2 : reel shape emboss taping (SOP8,SOP-J8,SSOP-B8,TSSOP-B8,TSSOP-B8J)

TR: reel shape emboss taping (MSOP8)

None: Tube (DIP-T8)

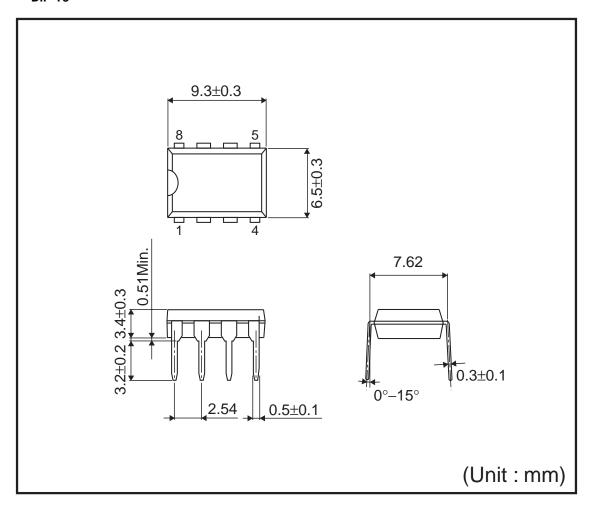
●Lineup

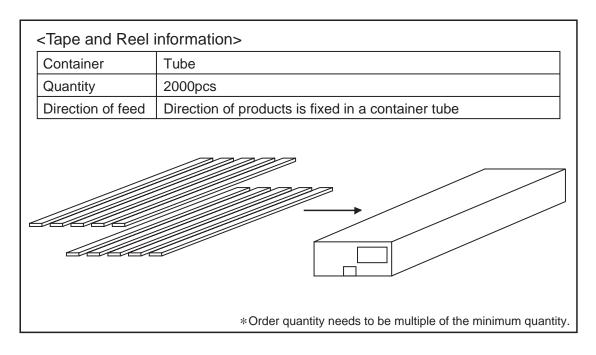
| Conneity | Package | | |
|----------|-----------|--------------|--|
| Capacity | Туре | Quantity | |
| | SOP8 | Reel of 2500 | |
| | SOP-J8 | | |
| 1K | SSOP-B8 | Reel of 2500 | |
| I IX | TSSOP-B8J | | |
| | TSSOP-B8 | Reel of 3000 | |
| | MSOP8 | Reel of 3000 | |
| | SOP8 | | |
| | SOP-J8 | Reel of 2500 | |
| 2K | SSOP-B8 | Reel of 2500 | |
| ZIX | TSSOP-B8J | | |
| | TSSOP-B8 | Reel of 3000 | |
| | MSOP8 | Reel of 3000 | |
| | DIP-T8 | Tube of 2000 | |
| 4K | SOP8 | | |
| | SOP-J8 | Reel of 2500 | |
| | SSOP-B8 | | |
| | TSSOP-B8J | | |
| | TSSOP-B8 | Reel of 3000 | |
| | MSOP8 | | |

| Consoity | Package | |
|----------|-----------|--------------|
| Capacity | Туре | Quantity |
| | DIP-T8 | Tube of 2000 |
| | SOP8 | |
| 8K | SOP-J8 | Reel of 2500 |
| | SSOP-B8 | |
| | TSSOP-B8 | Reel of 3000 |
| 16K | DIP-T8 | Tube of 2000 |
| | SOP8 | |
| | SOP-J8 | Reel of 2500 |
| | SSOP-B8 | |
| | TSSOP-B8 | Reel of 3000 |
| | DIP-T8 | Tube of 2000 |
| 32K | SOP8 | Reel of 2500 |
| | SOP-J8 | Reel 01 2500 |
| | DIP-T8 Tu | Tube of 2000 |
| 64K | SOP8 | Reel of 2500 |
| | SOP-J8 | Reel 01 2000 |

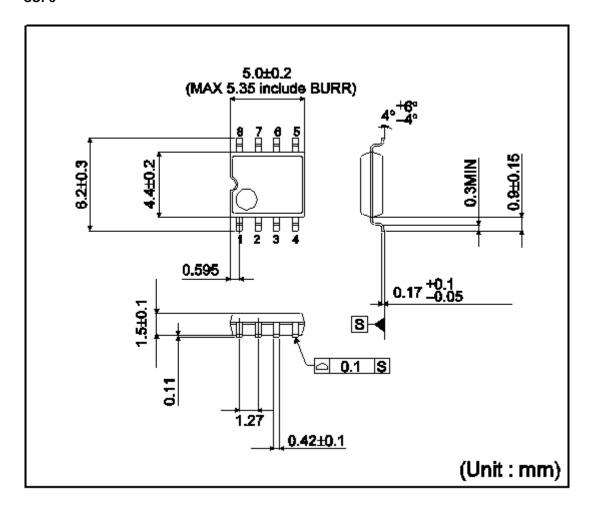
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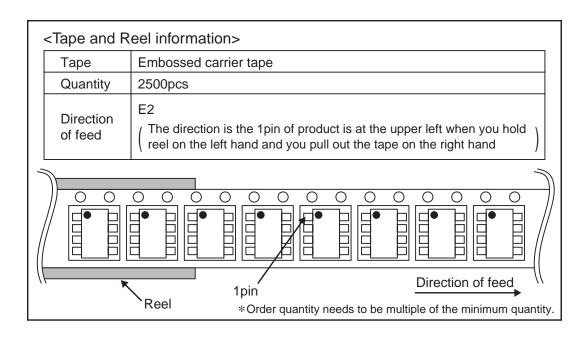
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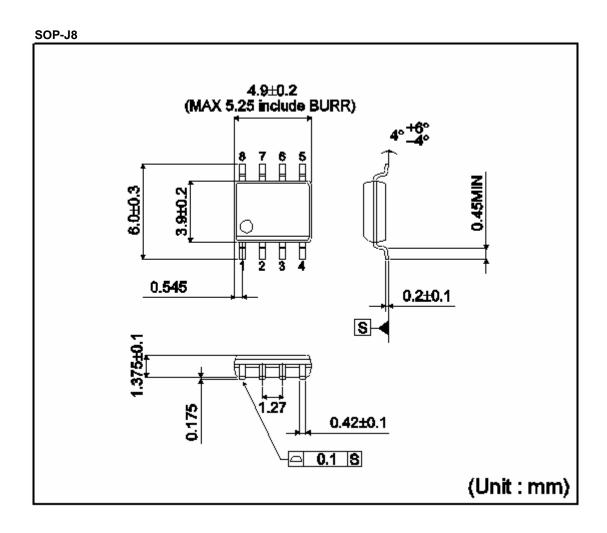


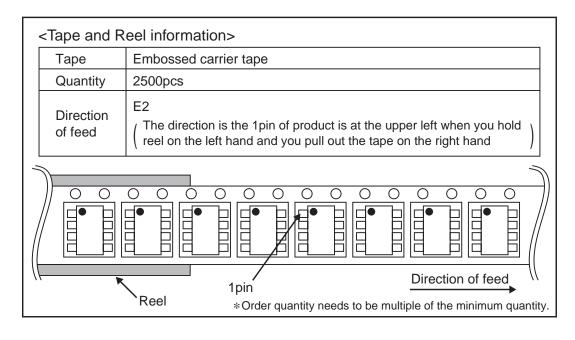


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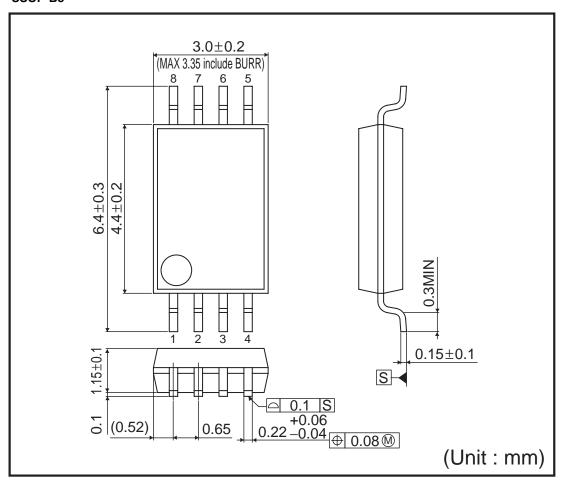


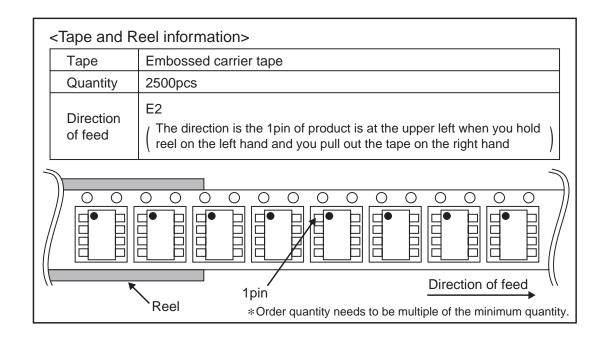




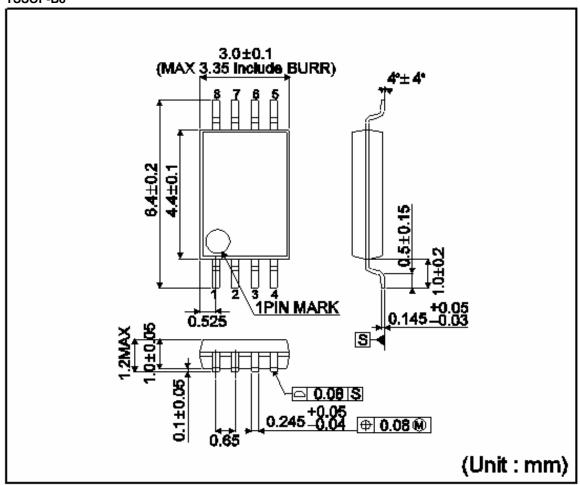


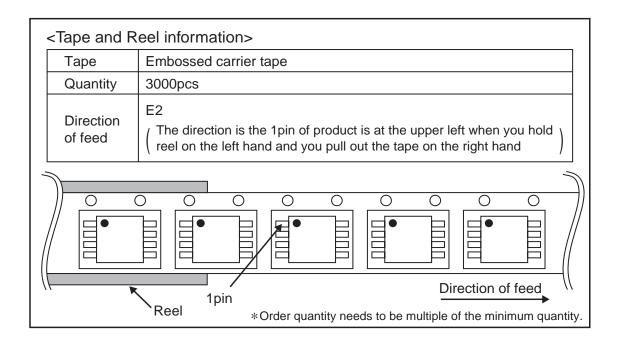
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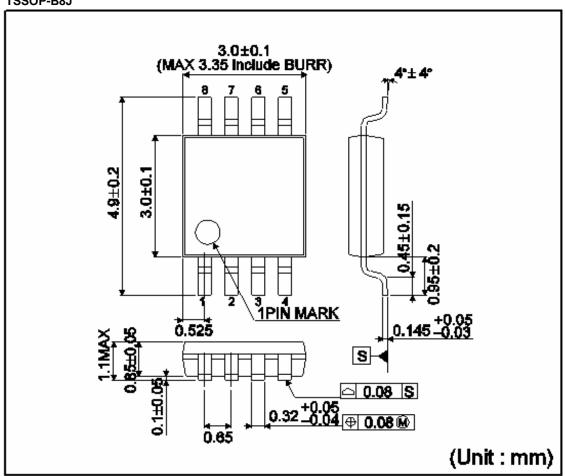


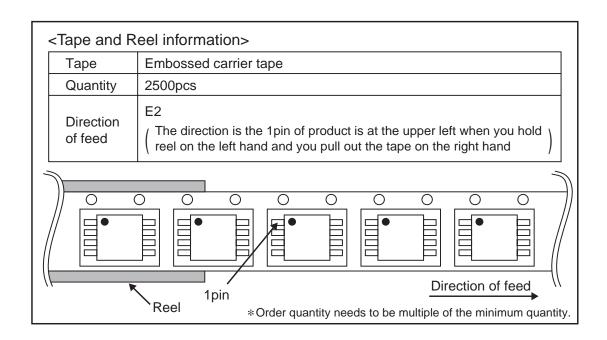
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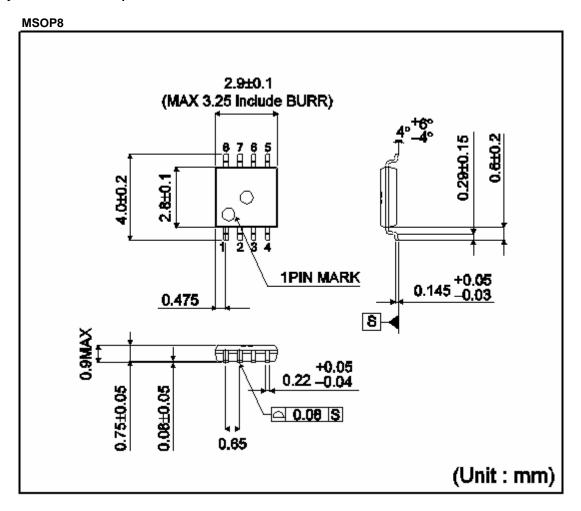


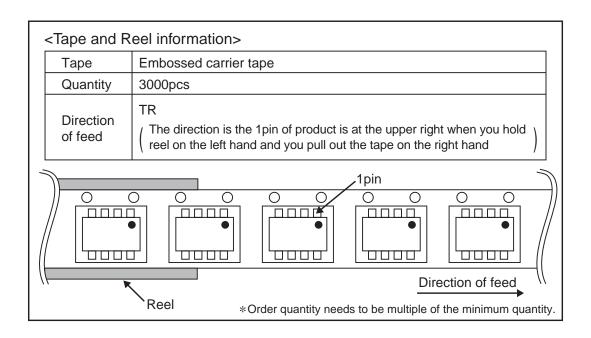


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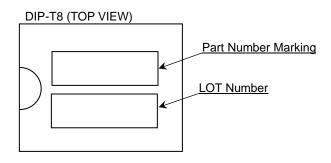


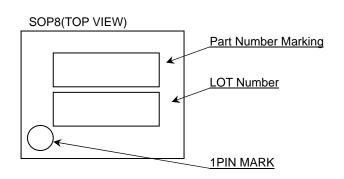


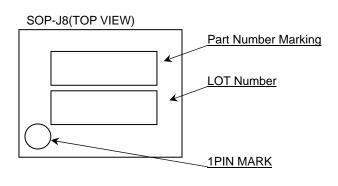


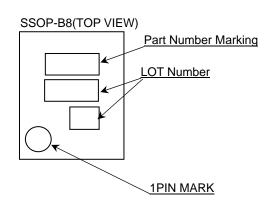


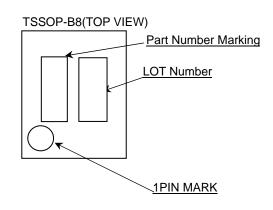
Marking Diagrams

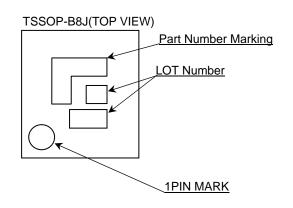


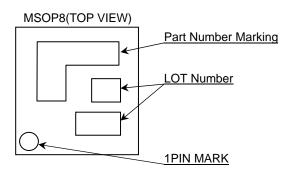












●Marking Information

| Capacity | Product Name Marking | Package Type | |
|----------|-------------------------|--------------|--|
| | L010 | SOP8 | |
| | L010 | SOP-J8 | |
| | L010 | SSOP-B8 | |
| 1K | L01 0 | TSSOP-B8J | |
| | L010 | TSSOP-B8 | |
| | L01 0 | MSOP8 | |
| | L020 | SOP8 | |
| | L020 | SOP-J8 | |
| 2K | L020 | SSOP-B8 | |
| | L02 0 | TSSOP-B8J | |
| | L020 | TSSOP-B8 | |
| | L02 0 | MSOP8 | |
| 4K | BR25L040 | DIP-T8 | |
| | L040 | SOP8 | |
| | L040 | SOP-J8 | |
| | L040 | SSOP-B8 | |
| | L04 0 | TSSOP-B8J | |
| | L040 | TSSOP-B8 | |
| | L04 0 | MSOP8 | |

| Capacity | Product Name Marking | Package Type | |
|----------|-------------------------|--------------|--|
| | BR25L080 | DIP-T8 | |
| | L080 | SOP8 | |
| 8K | L080 | SOP-J8 | |
| | L080 | SSOP-B8 | |
| | L080 | TSSOP-B8 | |
| | BR25L160 | DIP-T8 | |
| | L160 | SOP8 | |
| 16K | L160 | SOP-J8 | |
| | L160 | SSOP-B8 | |
| | L160 | TSSOP-B8 | |
| | BR25L320 | DIP-T8 | |
| 32K | L320 | SOP8 | |
| | L320 | SOP-J8 | |
| 64K | BR25L640 | DIP-T8 | |
| | L640 | SOP8 | |
| | L640 | SOP-J8 | |

●Revision History

| Date | Revision | Changes | |
|-------------|----------|--|--|
| 23.Aug.2012 | 001 | New Release | |
| 22.Jan.2013 | 002 | Add DIP-T8 Package (4K,8K,16K,32K,64K) | |

Notice

Precaution on using ROHM Products

Our Products are designed and manufactured for application in ordinary electronic equipments (such as AV equipment, OA equipment, telecommunication equipment, home electronic appliances, amusement equipment, etc.). If you intend to use our Products in devices requiring extremely high reliability (such as medical equipment (Note 1), transport equipment, traffic equipment, aircraft/spacecraft, nuclear power controllers, fuel controllers, car equipment including car accessories, safety devices, etc.) and whose malfunction or failure may cause loss of human life, bodily injury or serious damage to property ("Specific Applications"), please consult with the ROHM sales representative in advance. Unless otherwise agreed in writing by ROHM in advance, ROHM shall not be in any way responsible or liable for any damages, expenses or losses incurred by you or third parties arising from the use of any ROHM's Products for Specific Applications.

(Note1) Medical Equipment Classification of the Specific Applications

| JÁPAN | USA | EU | CHINA |
|---------|---------|------------|----------|
| CLASSI | СГУССШ | CLASS II b | СГУССШ |
| CLASSIV | CLASSII | CLASSIII | — CLASSⅢ |

- 2. ROHM designs and manufactures its Products subject to strict quality control system. However, semiconductor products can fail or malfunction at a certain rate. Please be sure to implement, at your own responsibilities, adequate safety measures including but not limited to fail-safe design against the physical injury, damage to any property, which a failure or malfunction of our Products may cause. The following are examples of safety measures:
 - [a] Installation of protection circuits or other protective devices to improve system safety
 - [b] Installation of redundant circuits to reduce the impact of single or multiple circuit failure
- 3. Our Products are designed and manufactured for use under standard conditions and not under any special or extraordinary environments or conditions, as exemplified below. Accordingly, ROHM shall not be in any way responsible or liable for any damages, expenses or losses arising from the use of any ROHM's Products under any special or extraordinary environments or conditions. If you intend to use our Products under any special or extraordinary environments or conditions (as exemplified below), your independent verification and confirmation of product performance, reliability, etc, prior to use, must be necessary:
 - [a] Use of our Products in any types of liquid, including water, oils, chemicals, and organic solvents
 - [b] Use of our Products outdoors or in places where the Products are exposed to direct sunlight or dust
 - [c] Use of our Products in places where the Products are exposed to sea wind or corrosive gases, including Cl₂, H₂S, NH₃, SO₂, and NO₂
 - [d] Use of our Products in places where the Products are exposed to static electricity or electromagnetic waves
 - [e] Use of our Products in proximity to heat-producing components, plastic cords, or other flammable items
 - [f] Sealing or coating our Products with resin or other coating materials
 - [g] Use of our Products without cleaning residue of flux (even if you use no-clean type fluxes, cleaning residue of flux is recommended); or Washing our Products by using water or water-soluble cleaning agents for cleaning residue after soldering
 - [h] Use of the Products in places subject to dew condensation
- 4. The Products are not subject to radiation-proof design.
- 5. Please verify and confirm characteristics of the final or mounted products in using the Products.
- 6. In particular, if a transient load (a large amount of load applied in a short period of time, such as pulse. is applied, confirmation of performance characteristics after on-board mounting is strongly recommended. Avoid applying power exceeding normal rated power; exceeding the power rating under steady-state loading condition may negatively affect product performance and reliability.
- 7. De-rate Power Dissipation (Pd) depending on Ambient temperature (Ta). When used in sealed area, confirm the actual ambient temperature.
- 8. Confirm that operation temperature is within the specified range described in the product specification.
- 9. ROHM shall not be in any way responsible or liable for failure induced under deviant condition from what is defined in this document.

Precaution for Mounting / Circuit board design

- 1. When a highly active halogenous (chlorine, bromine, etc.) flux is used, the residue of flux may negatively affect product performance and reliability.
- 2. In principle, the reflow soldering method must be used; if flow soldering method is preferred, please consult with the ROHM representative in advance.

For details, please refer to ROHM Mounting specification

Precautions Regarding Application Examples and External Circuits

- If change is made to the constant of an external circuit, please allow a sufficient margin considering variations of the characteristics of the Products and external components, including transient characteristics, as well as static characteristics.
- You agree that application notes, reference designs, and associated data and information contained in this document are presented only as guidance for Products use. Therefore, in case you use such information, you are solely responsible for it and you must exercise your own independent verification and judgment in the use of such information contained in this document. ROHM shall not be in any way responsible or liable for any damages, expenses or losses incurred by you or third parties arising from the use of such information.

Precaution for Electrostatic

This Product is electrostatic sensitive product, which may be damaged due to electrostatic discharge. Please take proper caution in your manufacturing process and storage so that voltage exceeding the Products maximum rating will not be applied to Products. Please take special care under dry condition (e.g. Grounding of human body / equipment / solder iron, isolation from charged objects, setting of lonizer, friction prevention and temperature / humidity control).

Precaution for Storage / Transportation

- 1. Product performance and soldered connections may deteriorate if the Products are stored in the places where:
 - [a] the Products are exposed to sea winds or corrosive gases, including Cl2, H2S, NH3, SO2, and NO2
 - [b] the temperature or humidity exceeds those recommended by ROHM
 - the Products are exposed to direct sunshine or condensation
 - [d] the Products are exposed to high Electrostatic
- 2. Even under ROHM recommended storage condition, solderability of products out of recommended storage time period may be degraded. It is strongly recommended to confirm solderability before using Products of which storage time is exceeding the recommended storage time period.
- 3. Store / transport cartons in the correct direction, which is indicated on a carton with a symbol. Otherwise bent leads may occur due to excessive stress applied when dropping of a carton.
- Use Products within the specified time after opening a humidity barrier bag. Baking is required before using Products of which storage time is exceeding the recommended storage time period.

Precaution for Product Label

QR code printed on ROHM Products label is for ROHM's internal use only.

Precaution for Disposition

When disposing Products please dispose them properly using an authorized industry waste company.

Precaution for Foreign Exchange and Foreign Trade act

Since our Products might fall under controlled goods prescribed by the applicable foreign exchange and foreign trade act, please consult with ROHM representative in case of export.

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Rev.001